


<b>Search Notes</b> 	<b>Application/Control No.</b> 10565274	<b>Applicant(s)/Patent Under Reexamination</b> OKUDA ET AL.
	<b>Examiner</b> Nguyen, Khien D	<b>Art Unit</b> 2823

### SEARCHED

Class	Subclass	Date	Examiner
257	40, 57, 59, 79	6/19/2007	K.N.
428	690, 917	6/19/2007	K.N.
257	40, E51.022	9/28/2009	/KN/
313	504, 506	9/28/2009	/KN/
428	690, 917	9/28/2009	/KN/

### SEARCH NOTES

Search Notes	Date	Examiner
EAST text search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB), see attached search history.	6/19/2007	K.N.
EAST text search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB), see attached search history.	2/7/2008	K.N.
EAST text search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB), see attached search history.	2/5/2009	/KN/
EAST text search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB), see attached search history.	9/27/2009	/KN/

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
	Claims interference searched (US-PGPUB; USPAT), see attached search history.	9/28/2009	/KN/

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Primary Examiner.Art Unit 2823